PIC-based system development: From idea to product

EPIC Technology Workshop on PIC Post-Processing & Packaging at the LASER World of PHOTONICS

Elvis Wan 29 June 2023







PhotonFirst develops and produces Photonic Integrated Circuits (PIC)- based sensing systems





photonic systems are based on **PICs**: tion of optical functionalities onto a

chip



PIC **packaging**: connecting and protecting the PIC to and from the application environment







Customer's asset (for example wind turbine)



Fiber with fiber bragg grating (FBG)



PIC Packaging: To Connect and Protect

Environmental conditions external

- Temperature (Env. range, dynamics)
- Mechanical (vibrations, shocks, stress)
- Radiation (sunlight, radiation, EMI)
- Materials (reactivity, oxidation, humidity)
- Operational (electric current, IR light)



Environmental needs internal (PIC)

- Temperature setpoint, stability
- Mechanical (connectivity, stress)
- Radiation (radiation, EMI)
- Protection (humidity, hermiticity, coatings)
- Operational (electric current, IR light)

In packaging the application and PICs meet:

- User needs and use (environment) conditions
- PIC function and functional (environment) conditions



From Concept to Product







Technology readiness levels (TRL)

The TRL levels for a PIC based system in development:







Conceptual & Theoretical study (TRL 1-2)

A development starts with an idea or customer request:

Translate idea or request into requirements:

- What should the system measure
- In which environment should the system operate
- What regulation should the system meet (Law, safety, et
- What should be the lifetime of components
- Performance vs Cost







TRL 3 Feasibility study (Simulation and experiments)

Analytical & laboratory tests. Separate building blocks on test bench

Design of a PIC in this phase to explore feasibility:

- Explore the building blocks required,
- Which building blocks are available and known
- Development of new building blocks in this phase

Think on how the chip should be tested:

- Separate test circuits of critical buidling blocks
- How will optical connection be made? (PIC-PIC, PIC-fiber?)
- Can you make all the design conclusions based on the test-circuits?

<u>"Make your life easy"</u>

- Developing a package or new test setup is expensive.
- Make your PIC design compatible with existing test setups
- Make your PIC design compatible with existing packaging solution





From idea to proof of concept (TRL 3-4)





- From building blocks to overall integrated design
 - Foundry specific, design rules
- Be specific in what is new (ASPIC), requires testing
 - Aggregation of functions / Building blocks
 - Actual performance of building blocks for your features/conditions of interest
 - Design for testing / demonstrator packaging





- Generic test packages, ADC/DAC modules
- Test benches for opto-electronic testing







From demonstrator to prototype (TRL 5-6)

Selecting/developing the right package

- Connectivity •
- Protection •

Requirements \leftrightarrow Specifications Generic ↔ Tailored







Design for assembly and test







Design the chip/package with the package/chip in mind!









Prototype and pre-series (TRL 5-6)

Complete system in housing, tested in laboratory or simulated environment



DO-160 Environmental tests

Extensive test campaigns conducted on

- Chip level (lifetime, ESS, functional testing)
- Package/module level
- System level

Industrial, MIL, DO-160 test categories, HALT



Proton radiation tests on PIC Interrogator modules



Damp heat climate test chamber



Blade monitoring application example, using a gator system equipped with ext. sync option (Courtesy NLR, 1ntegrate)



Vibration & shock testing systems for rotorcraft applications





Product(ion) optimization (TRL 7-9, MRL)

- "One functional PIC, does not mean having product yet!"
- Valuable data from production and process for end-use, design, fab
 - Fabrication tolerances, yield
 - Production control, process KPIs
 - Statistical analysis and optimization of all related production steps
 - Validation on chip, package, system



Automated Die-tester at PhotonFirst



Map of measured central wavelength (KPI) distribution of a structure across wafer position.



ESD damage on PIC Photodiode



Production PIC batch in gel-pack





Volume PIC Testing

• Test facility for full opto-electronic characterization, testing, qualification



• Full die-testing process automated for volume production PICs







Standardized PIC packaging capabilities













JePPIX Demonstrator Open Call

Take advantage of funding available through our Demonstrator Open Call.



Submit the form to receive more info





Unleasing Indium Phospide PIC Technology Design, manufacturing and testing services for pilot production



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